


<b>PCN Number:</b>	20230522003.1		<b>PCN Date:</b>	May 24, 2023																							
<b>Title:</b>	Qualification of CFAB and DFAB8 as additional Fab sites for Select LBC4 Devices																										
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>		<b>Dept:</b>	Quality Services																							
<b>Proposed 1<sup>st</sup> Ship Date:</b>	Aug 24, 2023		<b>Sample requests accepted until:</b>	Jun 24, 2023*																							
<b>*Sample requests received after Jun 24, 2023 will not be supported.</b>																											
<b>Change Type:</b>																											
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials																						
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification																						
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process																						
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process																						
<input checked="" type="checkbox"/>	Wafer Fab Site	<input checked="" type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process																						
		<input type="checkbox"/>	Part number change																								
<b>PCN Details</b>																											
<b>Description of Change:</b>																											
Qualification of additional Fab sites (CFAB & DFAB8) using qualified Process Technology for the list of devices in the product affected section below.																											
<table border="1"> <thead> <tr> <th colspan="3">Current Fab Site</th> <th colspan="3">Additional Fab site</th> </tr> <tr> <th>Current Fab Site</th> <th>Process</th> <th>Wafer Diameter</th> <th>Additional Fab site</th> <th>Process</th> <th>Wafer Diameter</th> </tr> </thead> <tbody> <tr> <td>DL-LIN</td> <td>LBC4</td> <td>150mm</td> <td>CFAB</td> <td rowspan="2">LBC4</td> <td rowspan="2">200mm</td> </tr> <tr> <td></td> <td></td> <td></td> <td>DL-LIN</td> </tr> </tbody> </table>						Current Fab Site			Additional Fab site			Current Fab Site	Process	Wafer Diameter	Additional Fab site	Process	Wafer Diameter	DL-LIN	LBC4	150mm	CFAB	LBC4	200mm				DL-LIN
Current Fab Site			Additional Fab site																								
Current Fab Site	Process	Wafer Diameter	Additional Fab site	Process	Wafer Diameter																						
DL-LIN	LBC4	150mm	CFAB	LBC4	200mm																						
			DL-LIN																								
Qual details are provided in the Qual Data Section.																											
<b>Reason for Change:</b>																											
These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.																											
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>																											
None																											
<b>Impact on Environmental Ratings</b>																											
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.																											
<b>RoHS</b>		<b>REACH</b>		<b>Green Status</b>																							
<input checked="" type="checkbox"/> No Change		<input checked="" type="checkbox"/> No Change		<input checked="" type="checkbox"/> No Change																							
<b>Changes to product identification resulting from this PCN:</b>																											
<b>Fab Site Information:</b>																											
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City																								
DL-LIN	DLN	USA	Dallas																								
<b>CFAB</b>	<b>CU3</b>	<b>CHN</b>	<b>Chengdu</b>																								

Sample product shipping label (not actual product label)



**TEXAS  
INSTRUMENTS**


MADE IN: Malaysia  
2DC: 20:

MSL 2 / 260C/1 YEAR	SEAL DT
MSL 1 / 235C/UNLIM	03/29/04

OPT:  
ITEM: 39

**LBL: 5A (L)T0:1750**





(1P) **SN74LS07NSR**

(Q) **2000** (D) **0336**

(31T) LOT: 3959047MLA

(4W) TKY (1T) 7523483SI2

(P)

(2P) REV: (V) 0000017

(20L) CS0: SHE (21L) CC0:USA

(22L) AS0: MLA (23L) AC0: MYS

**Product Affected:**

UCC2897APW	UCC2897APWR	UCC2897ARGPR	UCC2897ARGPT
UCC2897APW/1	UCC2897APWR/1		

For alternate parts with similar or improved performance, please visit the product page on [TI.com](https://www.ti.com)



**TI Information  
Selective Disclosure**

**Qualification Results**

**Data Displayed as: Number of lots / Total sample size / Total failed**

Type	Test Name / Condition	Duration	Qual Device: SN65HVD1040AQDRQ1
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hours	3/135/0
HTOL	Life Test, 125C	1000 Hours	3/231/0
ELFR	Early Life Failure Rate, 125C	48 Hours	3/2400/0
HBM	ESD - HBM	4000 V	1/3/0
HBM	ESD - HBM (Pin 5)	10000 V	1/3/0
HBM	ESD - HBM (Pin 6 & 7)	12000 V	1/3/0
CDM	ESD - CDM	1500 V	1/3/0
LU	Latch-up	(per JESD78)	1/6/0
ED	Electrical Distributions	Per Datasheet parameters	3/90/0

- QBS: Qual by Similarity
- Qual Device SN65HVDA1040AQDRQ1 qualified at LEVEL1-260C

**A1 (PC): Preconditioning:**

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

**Ambient Operating Temperature by Automotive Grade Level:**

Grade 0 (or E): -40°C to +150°C

Grade 1 (or Q): -40°C to +125°C

Grade 2 (or T): -40°C to +105°C

Grade 3 (or I): -40°C to +85°C

**E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):**

Room/Hot/Cold: HTOL, ED

Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room: AC/uHAST

**Green/Pb-free Status:**

Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20170424-121679



TI Information  
Selective Disclosure

**Qualification Results**  
Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: UCC2897APWR	QBS Process Reference: TLC5970RHPR	QBS Package Reference: TPS53123PW	QBS Package Reference: SN74LVT574PW
HTOL	Life Test, 125C	1000 Hours	-	3/231/0	-	-
HTSL	High Temp Storage Bake 170C	420 Hours	-	3/231/0	-	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	-	3/231/0	-	3/231/0
AC	Autoclave 121C	96 Hours	-	3/231/0	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	-	3/231/0	3/231/0	3/231/0
HBM	ESD - HBM	2500 V	1/3/0	-	-	-
HBM	ESD - HBM	2000 V	-	3/9/0	-	-
CDM	ESD - CDM	1500 V	1/3/0	-	-	-
CDM	ESD - CDM	500 V	-	3/9/0	-	-
LU	Latch-up	(per JESD78)	1/3/0	3/18/0	-	-
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	1/30/0	-	-
MQ	Assembly MQ	Per Site Specifications	Pass	Pass	Pass	Pass

- QBS: Qual By Similarity
- Qual Device UCC2897APWR is qualified at LEVEL1-260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

**Green/Pb-free Status:**

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2302-053

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	<a href="mailto:PCN_ww_admin_team@list.ti.com">PCN_ww_admin_team@list.ti.com</a>

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